

**Search Notes**

Application/Control No.

09/954,937

Examiner

Hai V. Nguyen

Applicant(s)/Patent under  
Reexamination

ITOH ET AL.

Art Unit

2142

**SEARCHED**

Class	Subclass	Date	Examiner
ABOVE	Updated	2/19/2007	HN
709	220, 221	2/20/2007	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated EAST search (USPGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) (see search history printout report)	2/19/2007	HN
Limited classified search: 709/220, 221 (see search history printout report)	2/20/2007	HN